

## 30V N-Channel Enhancement Mode MOSFET

### Description

The AP120N03BD uses advanced trench technology to provide excellent  $R_{DS(ON)}$ , low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

### General Features

$V_{DS} = 30V$   $I_D = 120A$

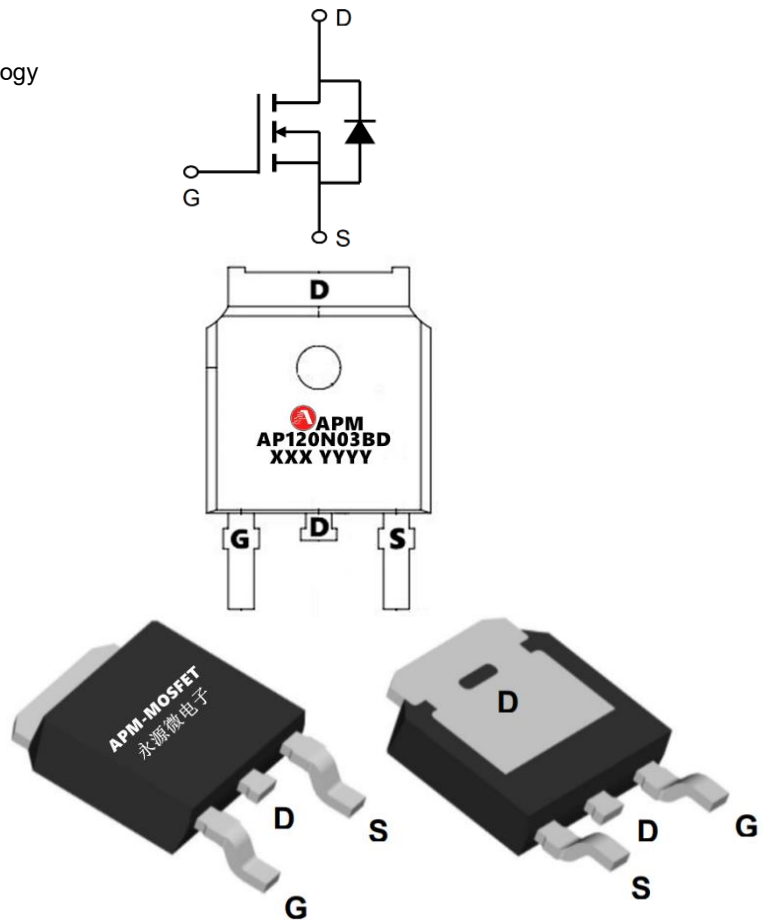
$R_{DS(ON)} < 3.8m\Omega$  @  $V_{GS}=10V$  (Type: 2.8m $\Omega$ )

### Application

Battery protection

Load switch

Uninterruptible power supply



### Package Marking and Ordering Information

| Product ID | Pack      | Marking             | Qty(PCS) |
|------------|-----------|---------------------|----------|
| AP120N03BD | TO-252-3L | AP120N03BD XXX YYYY | 2500     |

### Absolute Maximum Ratings ( $T_C=25^{\circ}C$ unless otherwise noted)

| Symbol                 | Parameter                                        | Rating     | Units         |
|------------------------|--------------------------------------------------|------------|---------------|
| $V_{DS}$               | Drain-Source Voltage                             | 30         | V             |
| $V_{GS}$               | Gate-Source Voltage                              | $\pm 20$   | V             |
| $I_D@T_C=25^{\circ}C$  | Continuous Drain Current, $V_{GS} @ 10V^1$       | 120        | A             |
| $I_D@T_C=100^{\circ}C$ | Continuous Drain Current, $V_{GS} @ 10V^1$       | 84         | A             |
| $I_{DM}$               | Pulsed Drain Current <sup>2</sup>                | 480        | A             |
| $E_{AS}$               | Single Pulse Avalanche Energy <sup>3</sup>       | 355        | mJ            |
| $I_{AS}$               | Avalanche Current                                | 36         | A             |
| $P_D@T_C=25^{\circ}C$  | Total Power Dissipation <sup>4</sup>             | 59         | W             |
| $T_{STG}$              | Storage Temperature Range                        | -55 to 150 | $^{\circ}C$   |
| $T_J$                  | Operating Junction Temperature Range             | -55 to 150 | $^{\circ}C$   |
| $R_{\theta JC}$        | Thermal Resistance Junction-Case <sup>1</sup>    | 2.1        | $^{\circ}C/W$ |
| $R_{\theta JA}$        | Thermal Resistance Junction-Ambient <sup>1</sup> | 62.5       | $^{\circ}C/W$ |

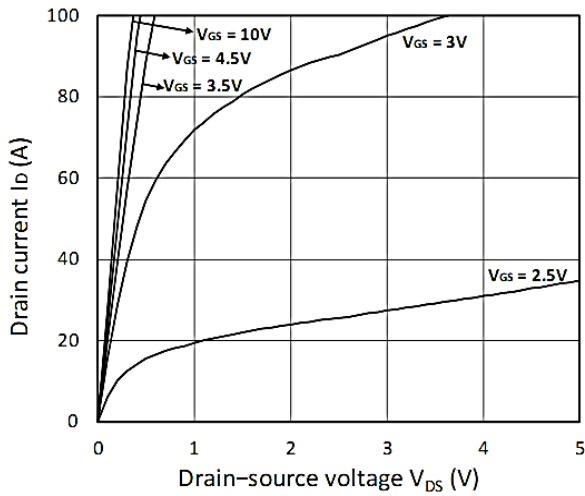
**30V N-Channel Enhancement Mode MOSFET**
**Electrical Characteristics ( $T_J=25^{\circ}\text{C}$ , unless otherwise noted)**

| Symbol  | Parameter                                | Conditions                                          | Min. | Typ. | Max.      | Unit       |
|---------|------------------------------------------|-----------------------------------------------------|------|------|-----------|------------|
| BVDSS   | Drain-Source Breakdown Voltage           | $V_{GS}=0V, I_D=250\mu A$                           | 30   | 34   | -         | V          |
| RDS(ON) | Static Drain-Source On-Resistance        | $V_{GS}=10V, I_D=30A$                               | -    | 2.8  | 3.8       | m $\Omega$ |
|         |                                          | $V_{GS}=4.5V, I_D=15A$                              | -    | 4.7  | 5.8       |            |
| VGS(th) | Gate Threshold Voltage                   | $V_{GS}=V_{DS}, I_D=250\mu A$                       | 1.2  | 1.5  | 2.5       | V          |
| IDSS    | Drain-Source Leakage Current             | $V_{DS}=30V, V_{GS}=0V, T_J=25^{\circ}\text{C}$     | -    | -    | 1         | uA         |
|         |                                          | $V_{DS}=30V, V_{GS}=0V, T_J=55^{\circ}\text{C}$     | -    | -    | 5         |            |
| IGSS    | Gate-Source Leakage Current              | $V_{GS}=\pm 20V, V_{DS}=0V$                         | -    | -    | $\pm 100$ | nA         |
| gfs     | Forward Transconductance                 | $V_{DS}=5V, I_D=30A$                                | -    | 22   | -         | S          |
| Rg      | Gate Resistance                          | $V_{DS}=15V, V_{GS}=0V, f=1\text{MHz}$              | -    | 1.7  | -         | $\Omega$   |
| Ciss    | Input Capacitance                        |                                                     | -    | 2320 | -         | pF         |
| Coss    | Output Capacitance                       |                                                     | -    | 293  | -         |            |
| Crss    | Reverse Transfer Capacitance             |                                                     | -    | 307  | -         |            |
| Qg      | Total Gate Charge (4.5V)                 | $V_{DS}=15V, V_{GS}=4.5V, I_D=15A$                  | -    | 20   | -         | nC         |
| Qgs     | Gate-Source Charge                       |                                                     | -    | 7.6  | -         |            |
| Qgd     | Gate-Drain Charge                        |                                                     | -    | 7.2  | -         |            |
| Td(on)  | Turn-On Delay Time                       | $V_{DD}=15V, V_{GS}=10V, R_G=3.3\Omega, I_D=15A$    | -    | 7.8  | -         | ns         |
| Tr      | Rise Time                                |                                                     | -    | 15   | -         |            |
| Td(off) | Turn-Off Delay Time                      |                                                     | -    | 37.3 | -         |            |
| Tf      | Fall Time                                |                                                     | -    | 10.6 | -         |            |
| Is      | Continuous Source Current <sup>1,5</sup> | $V_G=V_D=0V$ , Force Current                        | -    | -    | 100       | A          |
| ISM     | Pulsed Source Current <sup>2,5</sup>     |                                                     | -    | -    | 480       | A          |
| VSD     | Diode Forward Voltage <sup>2</sup>       | $V_{GS}=0V, I_S=1A, T_J=25^{\circ}\text{C}$         | -    | -    | 1         | V          |
| trr     | Reverse Recovery Time                    | $I_F=30A, dI/dt=100A/\mu s, T_J=25^{\circ}\text{C}$ | -    | 14   | -         | nS         |
| Qrr     | Reverse Recovery Charge                  |                                                     | -    | 5    | -         | nC         |

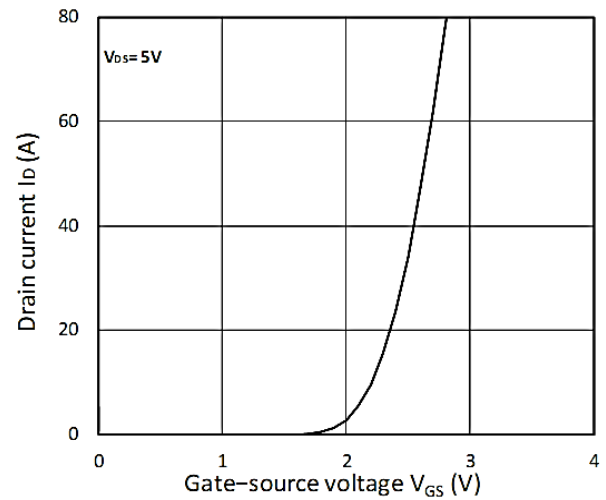
**Note :**

- 1、The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper.
- 2、The data tested by pulsed , pulse width  $\leq 300\mu s$  , duty cycle  $\leq 2\%$
- 3、The EAS data shows Max. rating . The test condition is  $V_{DD}=24V, V_{GS}=10V, L=0.1mH, I_{AS}=36A$
- 4、The power dissipation is limited by  $175^{\circ}\text{C}$  junction temperature
- 5、The data is theoretically the same as ID and IDM , in real applications , should be limited by total power dissipation.

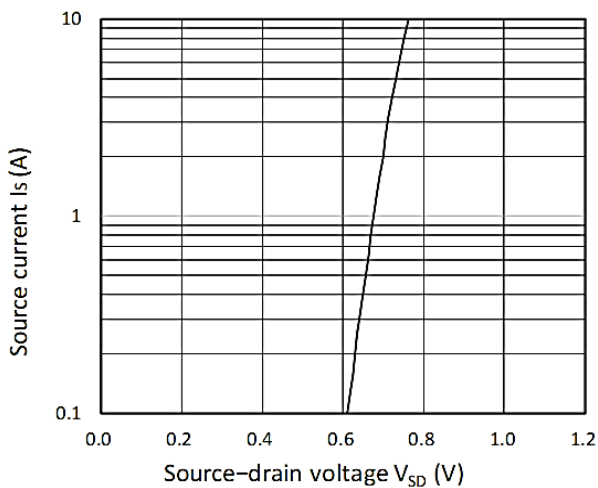
### Typical Characteristics



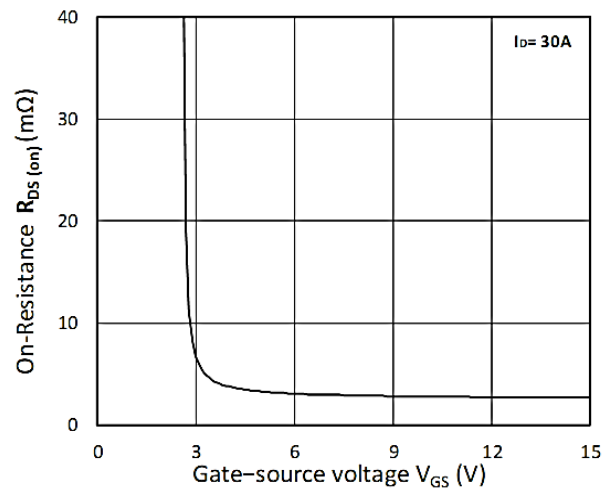
**Figure 1. Output Characteristics**



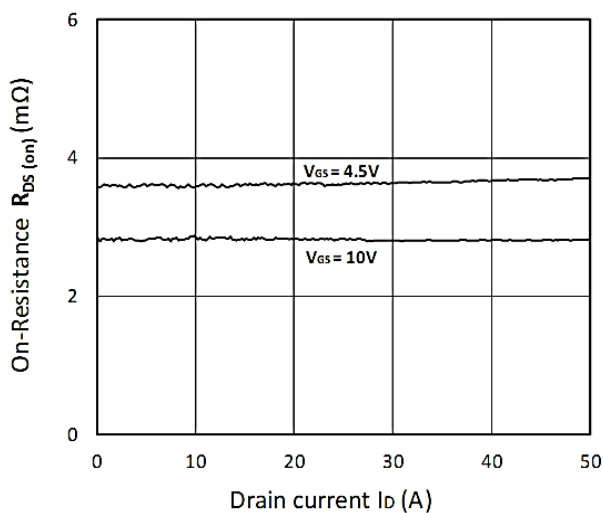
**Figure 2. Transfer Characteristics**



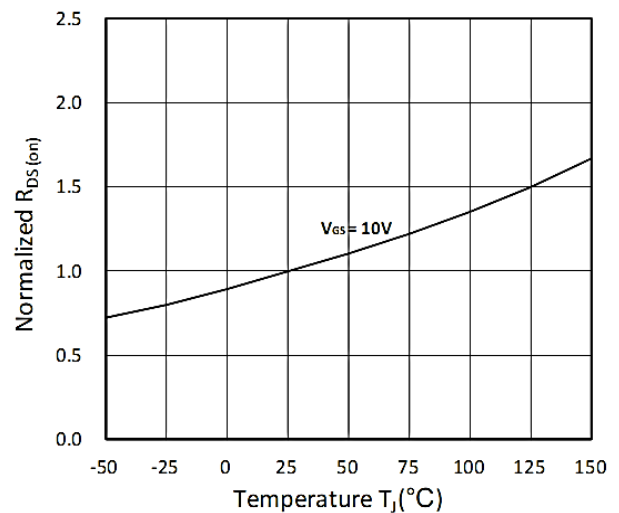
**Figure 3. Forward Characteristics of Reverse**



**Figure 4. R\_DS(ON) vs. V\_GS**

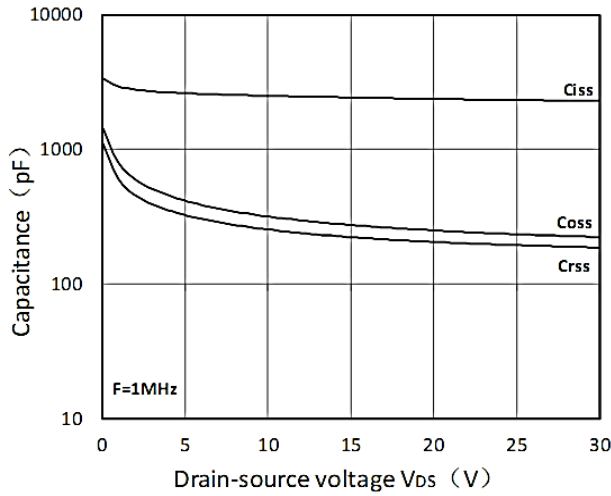


**Figure 5. R\_DS(ON) vs. I\_D**

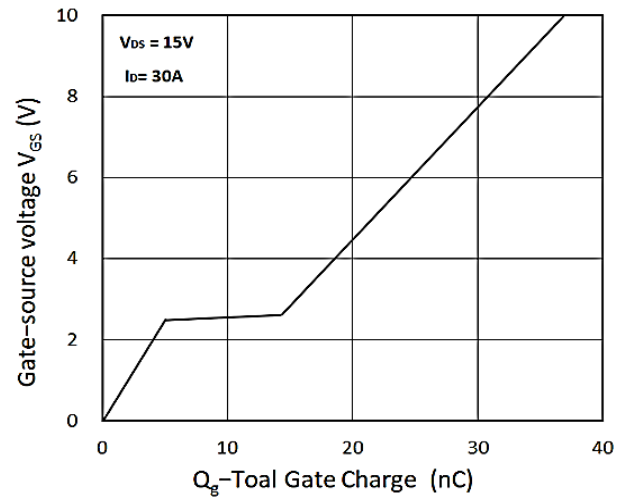


**Figure 6. Normalized R\_DS(on) vs. Temperature**

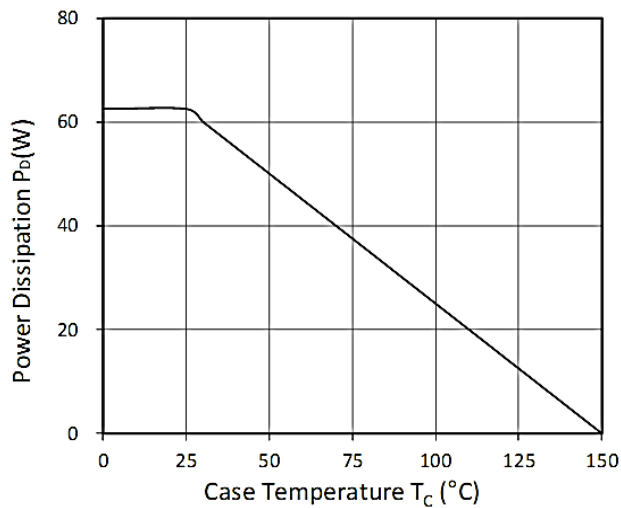
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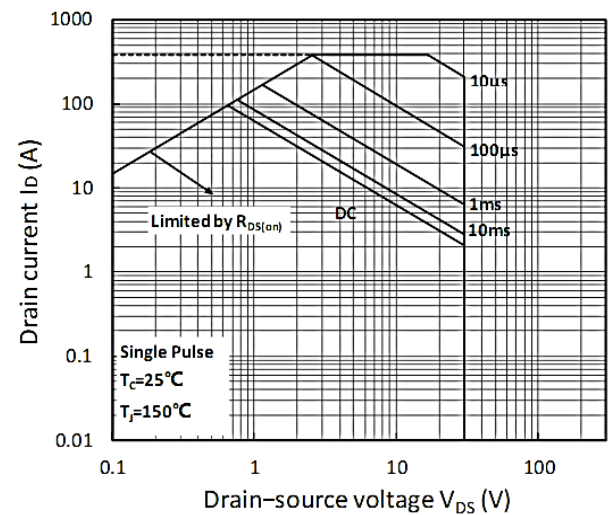
**Figure 7. Capacitance Characteristics**



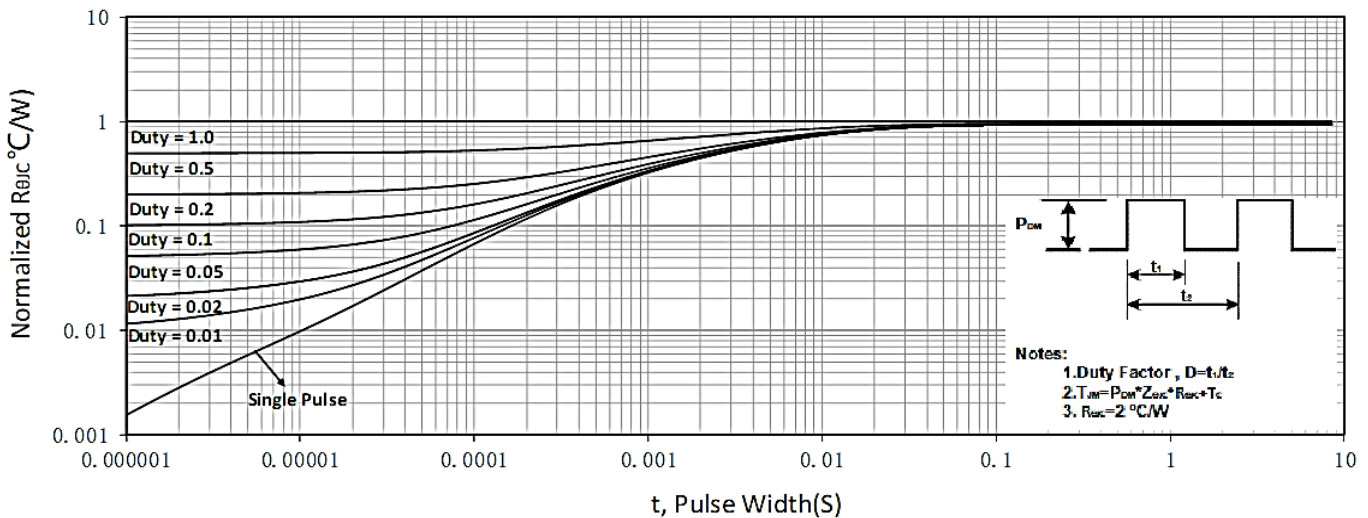
**Figure 8. Gate Charge Characteristics**



**Figure 9. Power Dissipation**

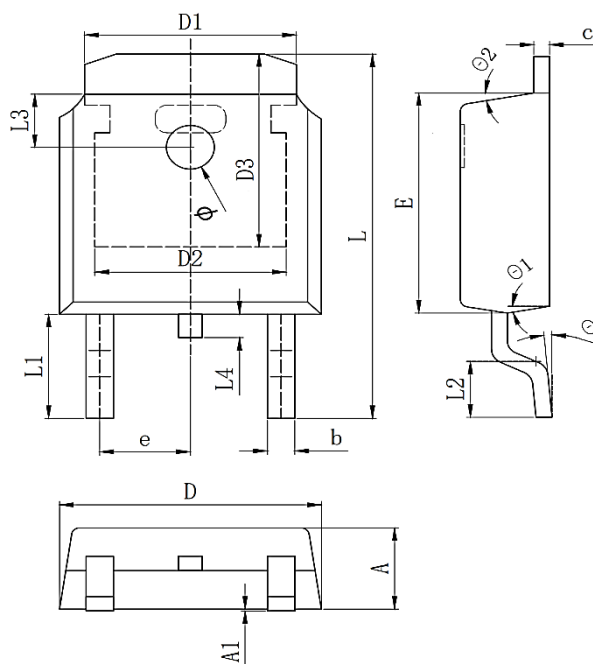


**Figure 10. Safe Operating Area**



**Figure 11. Normalized Maximum Transient Thermal Impedance**

## Package Mechanical Data-TO-252-3L



| Symbol | Dim in mm |       |       |
|--------|-----------|-------|-------|
|        | Min       | Typ   | Max   |
| A      | 2.1       | 2.3   | 2.5   |
| A1     | 0         | 0.064 | 0.128 |
| b      | 0.64      | 0.75  | 0.86  |
| c      | 0.45      | 0.52  | 0.6   |
| D      | 6.4       | 6.6   | 6.8   |
| D1     | 5.33REF   |       |       |
| D2     | 4.83REF   |       |       |
| D3     | 5.25REF   |       |       |
| E      | 5.9       | 6.1   | 6.3   |
| e      | 2.286TYP  |       |       |
| L      | 9.8       | 10.1  | 10.4  |
| L1     | 2.888REF  |       |       |
| L2     | 1.4       | 1.5   | 1.7   |
| L3     | 1.65REF   |       |       |
| L4     | 0.6       | 0.8   | 1     |
| φ      | 1.1       | 1.2   | 1.3   |
| θ      | 0°        |       | 10°   |
| θ1     | 5°        |       | 10°   |
| θ2     | 5°        |       | 10°   |

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